# <sup>25A</sup> 信昌電子陶瓷股份有限公司

### **Prosperity Dielectrics Co., Ltd.**

#### 1. INTRODUCTION

PROSPERITY's SAFETY CERTIFIED CAPACITORS are designed for surge or lightning immunity in modem facsimile and other equipments. The capacitors of FK series are class X1/Y2 compliant, and the capacitors of FH series are class X2 compliant respectively.

The green type capacitors in FK/FH series are manufactured by using environmentally friendly materials without lead or cadmium.

The terminations are composed of plated nickel and pure tin to feature the superior leaching resistance during soldering.

#### 2. FEATURES

- a. High reliability and stability.
- b. Small size and high capacitance.
- c. RoHS and HALOGEN compliant.
- d. AEC-Q200 qualified

#### 3. APPLICATIONS

- a. Modem
- b. Facsimile.
- c. Telephone.
- d. Other electronic equipment for lighting or surge protection and isolation.

#### 4. HOW TO ORDER

<u>FH</u>	<u>20</u>	<u>X</u>	<u>103</u>	<u>K</u>	<u>302</u>	<u>E</u>	<u>G</u>	<u>A</u>
PDC Family	Size	Dielectric	Capacitance	Tolerance	Impulse Voltage	Packaging	Thickness	Customer Code
Table 1	Table 2	Table 3	Table 4	Table 5	Table 6	Table 7	Table 8	Table 9

Table 1	PD	C Family
Code	D	escription
FK	Safety X1 & Y2 series	
FH	Safety X2 series	

Table 6		Impulse Voltage							
Code	Description	Code	Description	Code	Description				
252	7	302		502	5KV				
(FH06X)	2.5KV	(FH series)	2.5KV	602	6KV				

Tab	e 2	Size					
Code	De	scription	Code	Description	Code	Description	
06	1206	3 (3216)	12	1812 (4532)	20	2220 (5750)	
08	1808	3 (4520)	21	2211 (5728)			

Table 7		Packaging Type				
Code	Description	Code	Description			
B	Bulk	E	Embossed Tape			

Table 3	Dielectric Material Characteristics						
Code	Description	Code	Description				
N	C0G	X	X7R				

Tab	le 8		T	nickness Descr	<mark>iptio</mark> r	1
Code	De	escription	Code	Description	Code	Description
С	1.25	±0.10 mm	E	1.60±0.20 mm	G	2.50±0.30 mm
D	1.40:	±0.15 mm	F	2.00±0.20 mm	Н	2.80±0.30 mm

Table 4		Сар	acitance	Rule Code
Code		Description	Code	Description
0R5		0.5pF	104	104=10x10 <sup>4</sup> =100nF

Tal	ole 9	Customer Code						
Code	De	scription	Code	Description		Code	Description	
G	RoHs	compliant	Q	Ant	i-Arcing		Е	Anti-Bending
Н		Anti-Arcing+Anti-Bendin AEC-Q200 qualified			Z	Ar	nti-Arc	ing+Anti-Bendin
М	Automotive Capacitor Qualified to AEC-Q200 A AEC-Q200(No Anti-Arcing)							

Tabl	e 5	Tolerance					
Code	Des	cription	Code	Description	Code	Description	
D	±0.50 pF		G	±2 %	K	±10 %	
F	±	1 %	J	±5 %	М	±20 %	

Specification No.: FH-022-003-01 ~ 1 ~

# **Prosperity Dielectrics Co., Ltd.**

### **5. EXTERNAL DIMENSIONS**

Size Inch (mm)	2220(5750)	, L
L (mm)	5.70±0.50	<b>↑</b>
W (mm)	5.00±0.50	w
Code / T(mm)	G / 2.50±0.30	<del>«→ </del>   <del>«→ </del>
M <sub>B</sub> min.(mm)	0.60±0.30	Fig. 5.1 The outline of MLCC

### **6. GENERAL ELECTRICAL DATA**

Dielectric	た右 信 X7R					
Size	2220					
Rated voltage	250Vac					
Capacitance range	10nF					
Capacitance tolerance	K (±10%)					
Tan δ	≤2.5%					
	Measured at the condition of 30~70% related humidity					
Capacitance & Tan δ Test condition	Preconditioning for Class II MLCC:  Perform a heat treatment at 150±10°C for 1 hour, then leave in ambient condition for 24±2 hours before measurement					
	1.0±0.2Vrms, 1.0KHz±10%, at 25°C ambient temperature					
Insulation resistance	Diele ≥10GΩ or RxC≥500Ω-F, whichever is smaller					
Operating temperature	-55°C to +125°C					
Temperature coefficient	±15%					
Termination	Cu /Ni/Sn (lead-free termination)					

Specification No.: FH-022-003-01

## **Prosperity Dielectrics Co., Ltd.**

## 7. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Standard Methods	Test Condition	Requirement	S		
1.	Visual examination and Dimensions	IEC 60384-1 4.1		* No remarkable defect. * Dimensions to confirm to individual specification sheet.			
2.	Destructive Physical Analysis EIA-469		Per EIA-469.	* No defects or abnormalities.			
			* Capacitance. * D.F. (Dissipation Factor).	* Capacitance within the specified * D.F. value :	tolerance.		
			X7R: Apply 1.0±0.2Vrms, 1.0KHz±10%, at 25°C ambient temperature.	Dielectric Q/D.F. Class II (X7R) D.F.≤2.5%	Remark -		
			* Insulation Resistance.  Rated Vol.(V) Apply Voltage Charge Time  >500 500Vdc 60 sec.	* I.R. : ≥10GΩ or RxC≥500Ω-F, wh	nichever is smaller.		
3.	Electrical Characterizati on		* To apply voltage:  X capacitor: 1075Vdc (4.3UR).  Y capacitor: 1500Vac.  * Duration: 60 sec.  * The charge current shall not exceed 0.05A.  * The voltage shall be raised from the near zero to the test voltage a rate not exceeding 150V(r.m.s.)/sec.	* No evidence of damage or flash over during tes			
			* Temperature Coefficient (With no electrical load) Operation temperature : -55~125°C at 25°C.	* Capacitance Change : X7R withi	n ±15%.		
4.	Biased Humidity Ref. MIL-STD- 202 Method 103		* Test temperature: 85±3°C.  * Humidity: 85±5%RH.  * Test time: 1000 +24/-0 hrs.  * To apply voltage: Rated voltage (Max. 500Vdc) and 1.3~1.5Vdc (add 100k ohm resistor). Add apply 250Vac.  * Before initial measurement (Class II only): To apply test voltage for 1hr at test temp. and then set for 24±2 hrs at room temp.  * Measurement to be made after keeping at room temp. for 24±2 hrs.	* No remarkable damage.  * Cap. Change :     X7R : Within ±12.5%.  * Q/D.F. :     X7R : D.F.≤200% of initial requirement.  * I.R. : ≥500MΩ or RxC≥25Ω-F, whichever is smaller			
5.	Resistance to Soldering Heat Ref. MIL-STD- 202 Method 210	IEC 60384-14 4.4 IEC 60384- 21/22 4.9	* Solder temperature : 260±5°C.  * Dipping time : 10±1 sec.  * Reflow Soldering : Peak 260 +0/-5°C profile for Mega cap.  * Before initial measurement (X7R only) : Perform 150 +0/-10°C for 1 hr and then set for 24±2 hrs at room temp.  * Measurement to be made after keeping at room temp. for 24±2 hrs.	* Appearance : No remarkable damage.  * Cap. change : X7R within ±7.5%.  * D.F. value : X7R to meet initial requirement.  * I.R. : To meet the initial requirement.			

Specification No.: FH-022-003-01 ~ 3 ~



# **Prosperity Dielectrics Co., Ltd.**

## 7. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Standard Methods	Test Condition			Requirements
6.	ESD Ref. AEC-Q200- 002	our	* Per AE	EC-Q200-002.		* No remarkable damage. * Cap.: Within the specified tolerance. * Q/D.F. value: To meet the initial requirement. * I.R.: To meet the initial requirement.
7.	Temperature Cycle Ref. JESD22 Method JA-104	IEC 60384- 21/22 4.11	time. Step 1 2 3 4 * Measu	Temp.(°C) Min. operating temp. +0/-3 Room temp. Max. operating temp. +3/-0 Room temp. arement to be made after keeping temp.	Time(min.) 30±3 2~3 30±3 2~3	* Appearance : No remarkable damage.  * Cap. change : X7R within ±10.0%.  * D.F. value : X7R≤200% of initial requirement.  * I.R. : To meet initial requirement.
8.		IEC 60384-14 4.12	* Humid * Test tir * Measu	mp.: 25~65°C ity: 80~100% RH. me: 10 cycles, t=24hrs/cycle. Irement to be made after keepii for 48±4 hrs (Class II).	ing at room	* Appearance : No remarkable damage.  * Cap. change : X7R within ±12.5%.  * D.F. value : X7R : D.F.≤200% of initial requirement.  * I.R. : ≥1GΩ or RxC≥50Ω-F, whichever is smaller.
9.	Passive Flammability	IEC 60384-14 4.17 IEC 60384-1 4.38	* Volum * Flame	e sample : 21.56 mm³. exposure time : 5 sec. Max. ory of flammability : C.	O.H.I.	* Capacitor didn't burn at all.
10.	Active Flammability	IEC 60384-14 4.17 IEC 60384-1 4.38	sample tank cap discharg X1Y2 ad	apacitors applied UR (250Vac). shall be subjected to 20 discha pacitor, charge to a voltage that ged, places Ui 2500V for X2, Ui cross the capacitor under test. In successive discharges shall be	rges from a , when 5000V for The interval	* The cheese cloth shall not burn with a flame.
11.	Thermal shock Ref. MIL-STD- 202 Method 107		time.  Step  1  2  * Max. tr  * Before Perfore 24±2 r  * Measure	Temp.(°C)  Min. operating temp. +0/-3  Max. operating temp. +3/-0  ransfer time: 20 sec.  initial measurement (X7R only m 150 +0/-10°C for 1 hr and the ars at room temp.  Irement to be made after keeping for 24±2 hrs.	Time(min.)  15±3  15±3  15:  15:  15:  15:  15:  15:  15:  15	* Appearance : No remarkable damage.  * Cap. change : X7R within ±10.0%.  * D.F. value : X7R≤200% of initial requirement.  * I.R. : To meet initial requirement.

Specification No.: FH-022-003-01

## **Prosperity Dielectrics Co., Ltd.**

## 7. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Standard Methods	Test Condition	Requirements
12.	High Temperature Load (Endurance) Ref. MIL-STD- 202 Method 108	IEC 60384-14 4.14	* Impulse Voltage: Each individual capacitor shall be subjected to a Vp = 5.0KV (X1Y2 Class Impulse 5KV) or Vp = 2.5KV (X2 Class Impulse 2.5KV) impulse for three times before applied to endurance test. * Test time: 1000 +48/-0 hrs. * Applied voltage: X capacitor: 1.25U <sub>R</sub> (312.5Vac). Y capacitor: 1.70U <sub>R</sub> (425Vac). Once every hour the voltage shall be increased to 1000Vrms for 0.1 sec. * Measurement to be made after keeping at room temp. for 48±4 hrs (Class II) * An additional test of 750Vdc (120% of the rated DC voltage) is added for safety-related automotive products.	* Appearance : No mechanical damage. * Cap. change : X7R within ±20%. * D.F. value : X7R : D.F.≤200% of initial requirement. * I.R. : ≥1GΩ.
13.	Resistance to Solvents Ref. MIL-STD- 202 Method 215		*Temperature : 25±5°C.  * Time : 3 +0.5/-0 min. SYSTEM ALLIANCE  * Solvent : Iso-propyl alcohol.	* No remarkable damage. * Cap. : Within the specified tolerance. * Q/D.F. value : To meet the initial requirement. * I.R. : To meet the initial requirement.
14.	Mechanical Shock Ref. MIL-STD- 202 Method 213		* Peak value : 1500g's.  * Wave : 1/2 sine.  * Velocity : 15.4 ft/sec.  * Three shocks in each direction should be applied along 3 mutually perpendicular axes of the test specimen (18 shocks).	* No remarkable damage.  * Cap. : Within the specified tolerance.  * Q/D.F. value : To meet the initial requirement.  * I.R. : To meet the initial requirement.
15.	Solderability Ref. J-STD- 002 JESD22- B102E		* Condition A Un-mounted chips 4hrs / 155°C*dry then completely immersed for 5±0.5 sec in solder bath at 245±5°C. (4hrs / 155°C*dry and peak 260 +0/-5°C reflow profile for Mega cap) * Condition B Un-mounted chips steam 8 hrs then completely immersed for 10±1sec in solder bath at 220 +5/-0°C. * Condition C Un-mounted chips steam 8 hrs then completely immersed for 10±1 sec. in solder bath at 260 +0/-5°C.	* All terminations shall exhibit a continuous solder coating free from defects from a minimum of 95% of the critical surface area of any individual termination.

Specification No.: FH-022-003-01 ~ 5 ~



## **Prosperity Dielectrics Co., Ltd.**

### 7. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Standard Methods	Test Condition	Requirements
16.	Board Flex Ref. AEC- Q200-005		* The middle part of substrate shall be pressurized by means of the pressurizing rod at a rate of about 1 mm per second until the deflection becomes 3mm and then the pressure shall be maintained for 60±1 sec.  * Measurement to be made after keeping at room temp. for 24±2 hrs.	* No remarkable damage.  * Cap. : Within the specified tolerance.  * Q/D.F. value : To meet the initial requirement.  * I.R. : To meet the initial requirement.  (This capacitance change means the change of capacitance under specified flexure of substrate from the capacitance measured before the test)
17.	Ref. AEC-	IEC 60384- 21/22 4.15 IEC 60384-1 4.13	* Pressurizing force : 2N(0402), 5N(0603), 10N(0805), 17.7N(≥1206). * Test time : 60±1 sec.	* No remarkable damage or removal of the terminations.
18.		IEC 60384-1 4.17	* Vibration frequency : 10~2000 Hz/min. (5g's for 20 min.).  * Total amplitude : 1.5mm.  * 12 cycles each of 3 orientations (36 times)	* No remarkable damage.  * Cap. : Within the specified tolerance.  * Q/D.F. value : To meet the initial requirement.  * I.R. : To meet the initial requirement.
19.	Beam Load Test Ref. AEC- Q200-003		* Break strength test. * Beam speed: 2.5±0.25 mm/sec.	The chip endure following force : Chip length ≤2.5mm : Thickness >0.5mm (20N), ≤0.5mm (8N). Chip length ≥3.2mm : Thickness ≥1.25mm (54.5N), <1.25mm (15N).

Specification No.: FH-022-003-01 ~ 6 ~



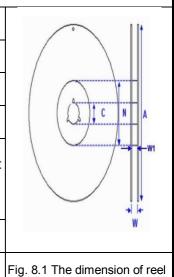
## 信昌電子陶瓷股份有限公司

## **Prosperity Dielectrics Co., Ltd.**

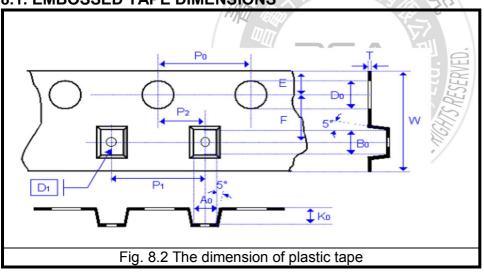
### **8. PACKAGE DIMENSION AND QUANTITY**

Circ	Thickness	Plastic tape		
Size	(mm)	7" reel	13" reel	
1206(3216)	1.25±0.10	3k	10k	
	1.25±0.10	2k	10k	
1909(4520)	1.40±0.15	2k	10k	
1808(4520)	1.60±0.20	2k	8k	
	2.00±0.20	1k	6k	
	1.25±0.10	1k	_	
1010(4520)	1.60±0.20	1k	_	
1812(4532)	2.00±0.20	1k	-	
	2.50±0.30	0.5k	3k	
	1.60±0.20	1k	-	
2211(5728)	2.00±0.20	1k	-	
2211(3726)	2.50±0.30	0.5k	-	
	2.80±0.30	0.5k	- //	
2220(5750)	2.00±0.20	1k	1 日 日	
2220(5750)	2.50±0.30	0.5k	2k	

Size       1206       1808, 1812, 2211, 2220         Reel size       7"       7"         C       13.0		ı	REEL DIMENS	SIONS
C 13.0 13.0	Size	1206		
W <sub>1</sub> +0.5/-0.2 +0.5/-0.2  W <sub>1</sub> 8.4 12.4 +1.5/-0 +2.0/-0  shall accommodat e tape width without interference  A 178.0 178.0 ±0.1  60.0 60.0 Fig. 8	Reel size	7"	7"	/
W <sub>1</sub> +1.5/-0 +2.0/-0 shall accommodat e tape width without interference  A 178.0 178.0 ±0.1 ±0.1	С			
W       14.4max       accommodat e tape width without interference         A       178.0	W <sub>1</sub>		l . <del>_</del>	
A ±0.1 ±0.1 60.0 Fig. 8	W	14.4max	accommodat e tape width without	
Lia Q	Α			
+1.0/-0   +1.0/-0   1.19. S.	N	60.0 +1.0/-0	60.0 +1.0/-0	Fig. 8.



#### 8.1. EMBOSSED TAPE DIMENSIONS



Size	1206	1808		1812		2211		2220	
Chip Thickness	1.25±0.10	1.25±0.10 1.40±0.15 1.60±0.20	2.00±0.20	1.25±0.10 1.60±0.20 2.00±0.20	2.50±0.30	1.60±0.20 2.00±0.20	2.50±0.30 2.80±0.30	2.00±0.20	2.50±0.30 2.80±0.30
A <sub>0</sub>	<2.00	<2.50	<2.50	<3.90	<3.90	<3.30	<3.30	<5.80	<5.80
B <sub>0</sub>	<3.60	<5.30	<5.30	<5.30	<5.30	<6.50	<6.50	<6.50	<6.50
T	0.23±0.05	0.25±0.05	0.25±0.05	0.25±0.05	0.25±0.05	0.30±0.10	0.30±0.10	0.30±0.10	0.30±0.10
K <sub>0</sub>	<2.50	<2.50	<2.50	<2.50	<3.00	<2.50	<3.10	<2.50	<3.10
W	8.00±0.10	12.00±0.20	12.00±0.20	12.00±0.20	12.00±0.20	12.00±0.20	12.00±0.20	12.00±0.20	12.00±0.20
P <sub>0</sub>	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10	4.00±0.10
10xP₀	40.00±0.20	40.00±0.20	40.00±0.20	40.00±0.20	40.00±0.20	40.00±0.20	40.00±0.20	40.00±0.20	40.00±0.20
P <sub>1</sub>	4.00±0.10	4.00±0.10	4.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10	8.00±0.10
P <sub>2</sub>	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05	2.00±0.05
$D_0$	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0	1.50+0.10/-0
D <sub>1</sub>	1.00±0.10	1.50±0.10	1.50±0.10	1.50±0.10	1.50±0.10	1.50±0.10	1.50±0.10	1.50±0.10	1.50±0.10
E	1.75±0.10	1.75±0.10	1.75±0.10	1.75±0.10	1.75±0.10	1.75±0.10	1.75±0.10	1.75±0.10	1.75±0.10
F	3.50±0.05	5.50±0.05	5.50±0.05	5.50±0.05	5.50±0.05	5.50±0.05	5.50±0.05	5.50±0.05	5.50±0.05
Unit:	mm	mm	mm	mm	mm	mm	mm	mm	mm

Specification No.: FH-022-003-01 ~ 7 ~

### **Prosperity Dielectrics Co., Ltd.**

#### 9. APPLICATION NOTES

#### **STORAGE**

To prevent the damage of solderability of terminations, the following storage conditions are recommended:

Indoors under 5 ~ 40°C and 20% ~ 70% RH.

No harmful gases containing sulfuric acid, ammonia, hydrogen sulfide or chlorine.

Packaging should not be opened until the capacitors are required for use. If opened, the pack should be re-sealed as soon as is practicable. Taped product should be stored out of direct sunlight, which might promote deterioration in tape or adhesion performance. The product is recommended to be used within 12 months after shipment and checked the solderability before use.

#### **HANDLING**

Chip capacitors are dense, hard, brittle, and abrasive materials. They are liable to suffer mechanical damage, in the form of cracks or chips. Chip Capacitors should be handled with care to avoid contamination or damage. To use vacuum or plastic tweezers to pick up or plastic tweezers is recommended for manual placement. Tape and reeled packages are suitable for automatic pick and placement machine.

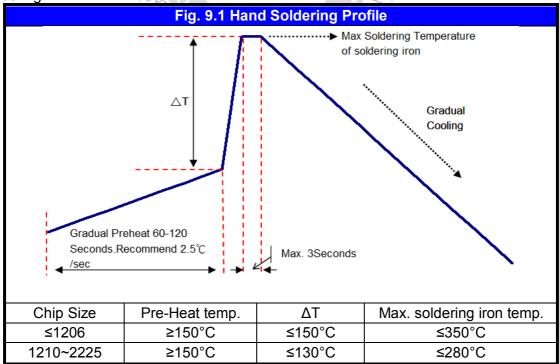
#### PREHEAT

In order to minimize the risk of thermal shock during soldering, a carefully controlled preheat is required. The rate of preheat should not exceed 3°C per second.

#### SOLDERING

Use mildly activated rosin fluxes do not use activated flux. The amount of solder in each solder joint should be controlled to prevent the damage of chip capacitors caused by the stress between solder, chips, and substrate.

a.) Hand soldering:



- \* Soldering iron tip diameter ≤1.0 mm and wattage max. 20W.
- \* The Capacitors shall be pre-heated and that the temperature gradient between the devices and the tip of the soldering iron.
- \* The required amount of solder shall be melted on the soldering tip.
- \* The tip of iron should not contact the ceramic body directly.
- \* The Capacitors shall be cooled gradually at room temperature after soldering.
- \* Forced air cooling is not allowed.

Specification No.: FH-022-003-01 ~ 8 ~

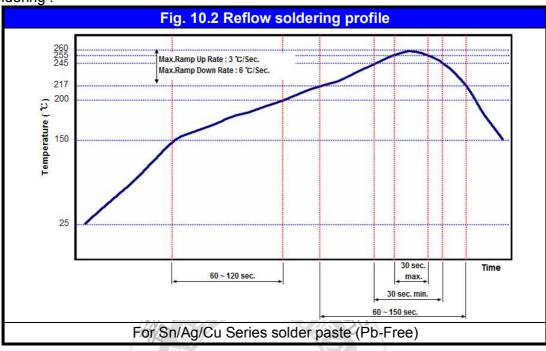


### **Prosperity Dielectrics Co., Ltd.**

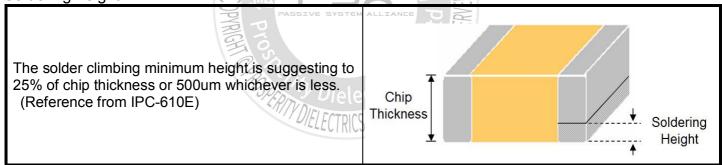
#### 9. APPLICATION NOTES

b.) Reflow soldering:





Soldering height:



#### COOLING

After soldering, cool the chips and the substrate gradually to room temperature. Natural cooling in air is recommended to minimize stress in the solder joint.

#### **CLEANING**

All flux residues must be removed by using suitable electronic-grade vapor-cleaning solvents to eliminate contamination that could cause electrolytic surface corrosion. Good results can be obtained by using ultrasonic cleaning of the solvent. The choice of the proper system is depends upon many factors such as component mix, flux, and solder paste and assembly method. The ability of the cleaning system to remove flux residues and contamination from under the chips is very important.

Surface coating products are not suitable cleaning/washing by solvent